

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/603,439	<b>Applicant(s)/Patent under Reexamination</b> SHAYLOR ET AL.
<b>Examiner</b> J. Derek Rutten	<b>Art Unit</b> 2192	

**SEARCHED**

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	3/7/2007	JDR
717/162-167; 713/2; 719/332 text search only See search history printout	3/8/2007	JDR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	3/8/2007	JDR
Tuan Dam (consulted re. allowable subj. matter)	3/8/2007	JDR
ACM - portal.acm.org IEEE - ieeexplore.ieee.org See search history printout	3/8/2007	JDR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See search notes			